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# Optical Systems and Modern Optoelectronic Instruments

Juan Liu Baohua Jia Xincheng Yao Yongtian Wang Takanori Nomura Editors

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## Introduction

This year in Beijing, China, we held the seventh conference of Optical Systems, Optoelectronic Instruments, Novel Display and Imaging Technology, which has been a sub-conference of OIT since its inauguration in 2008. In 2019, we selected 34 oral presentations from over 90 submissions to this sub-conference, including 22 invited talks. Experts from United States, Japan, Australia, and China attended the sub-conference in Beijing International Conference Center, and presented latest research findings. We also had an excellent attentive audience who provided many good questions.

There were five sessions in the sub-conference of Optical Systems and Modern Optoelectronic Instruments:

3D Display (session 1), Imaging and Instruments (session 2), Meta Structures and Plasmonics (session 3), Nano Fabrication and Structures (session 4), and Biophotonics (session 5).

We believe that this year's Optical Systems, Optoelectronic Instruments, Novel Display and Imaging Technology conference maintained its previous high standards, and we hope that the papers included in the Proceedings will prove valuable to our fellow scientists and engineers.

Juan Liu Baohua Jia Xincheng Yao Yongtian Wang Takanori Nomura

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